Constraint-based hierarchical untestability identification for synchronous sequential circuits

Raik, Jaan; **Rannaste, Anna**; **Jenihhin, Maksim**; **Viilukas, Taavi**; **Ubar, Raimund-Johannes**; Fujiwara, Hideo Sixteenth IEEE European Test Symposium : 23-27 May 2011, Trondheim 2011 / p. 147-152